



## N-Channel Enhancement MOSFET

### Features

- Drain-Source Breakdown Voltage  $V_{DS} = 20V$
- Drain-Source On-Resistance  
 $R_{DS(ON)} 23m\Omega$ , at  $V_{GS} = 4.5V$ ,  $I_D = 5.0A$   
 $R_{DS(ON)} 27m\Omega$ , at  $V_{GS} = 2.5V$ ,  $I_D = 3.5A$   
 $R_{DS(ON)} 34m\Omega$ , at  $V_{GS} = 1.8V$ ,  $I_D = 2.8A$
- Continuous Drain Current at  $T_C = 25^\circ C$   $I_D = 9.0A$
- Advanced high cell density Trench Technology
- RoHS Compliance & Halogen Free

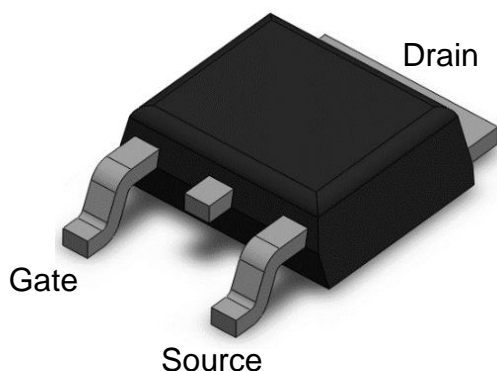
### Description

The CT8124 –T52 uses high performance Trench Technology to provide excellent  $R_{DS(ON)}$  and low gate charge which is suitable for most of the synchronous buck converter applications .

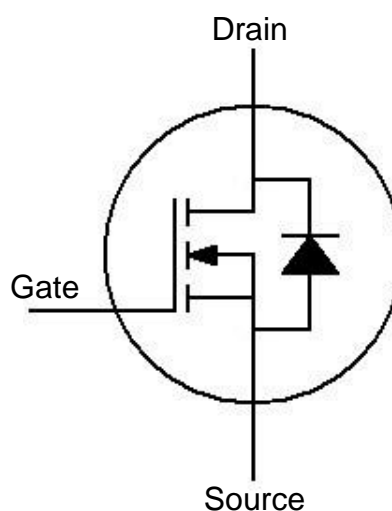
### Applications

- Notebook
- High side switching
- Power Management

### Package Outline



### Schematic



**N-Channel Enhancement MOSFET****Absolute Maximum Rating at 25°C**

Symbol	Parameters	Test Conditions	Min	Notes
V <sub>DS</sub>	Drain-Source Voltage	20	V	
V <sub>GS</sub>	Gate-Source Voltage	±8	V	
I <sub>D</sub>	Continuous Drain Current @T <sub>C</sub> =25°C	9	A	1
I <sub>DM</sub>	Pulsed Drain Current	30	A	1
P <sub>D</sub>	Total Power Dissipation @T <sub>C</sub> =25°C	2.5	W	2
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150	°C	

**Thermal Characteristics**

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
R <sub>θJC</sub>	Thermal Resistance Junction-Case	Steady State	--	--	4.5	°C /W	1,3



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Electrical Characteristics  $T_A = 25^\circ\text{C}$  (unless otherwise specified)

## Static Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$B_{V_{DS}}$	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	20	-	-	V	
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS} = 20V, V_{GS} = 0V$	-	-	1	$\mu A$	
$I_{GSS}$	Gate-Source Leakage Current	$V_{GS} = \pm 8V, V_{DS} = 0V$	-	-	$\pm 100$	nA	

## On Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$R_{DS(ON)}$	Drain-Source On-Resistance	$V_{GS} = 4.5V, I_D = 5.0A$	-	23	33	m $\Omega$	2
		$V_{GS} = 2.5V, I_D = 3.5A$	-	27	40	m $\Omega$	2
		$V_{GS} = 1.8V, I_D = 2.8A$	-	34	51	m $\Omega$	2
$V_{GS(th)}$	Gate-Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250\mu A$	0.4	-	1.5	V	2

## Dynamic Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$C_{ISS}$	Input Capacitance	$V_{GS} = 0V,$ $V_{DS} = 10V$ $f = 1MHz$	-	599	-	pF	
$C_{OSS}$	Output Capacitance		-	81	-		
$C_{RSS}$	Reverse Transfer Capacitance		-	73	-		

## Switching Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
$T_{D(ON)}$	Turn-On Delay Time	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $R_G = 6\Omega,$ $I_D = 3.6A$	-	3.5	-	ns	
$T_R$	Rise Time		-	23	-		
$T_{D(OFF)}$	Turn-Off Delay Time		-	39	-		
$T_F$	Fall Time		-	24	-		
$Q_G$	Total Gate Charge	$V_{DS} = 10V,$ $V_{GS} = 4.5V,$ $I_D = 4.5A$	-	7.5	-	nC	
$Q_{GS}$	Gate-Source Charge		-	1	-		
$Q_{GD}$	Gate-Drain (Miller) Charge		-	2	-		



## N-Channel Enhancement MOSFET

### Drain-Source Diode Characteristics

Symbol	Parameters	Test Conditions	Min	Typ	Max	Units	Notes
V <sub>SD</sub>	Body Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 4.5A	-	-	1.2	V	
I <sub>SD</sub>	Body Diode Continuous Current		-	-	4.5	A	1

Note:

1. The power dissipation is limited by 150°C junction temperature.
2. The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
3. Thermal Resistance follow JESD51-3.



### Typical Characteristic Curves

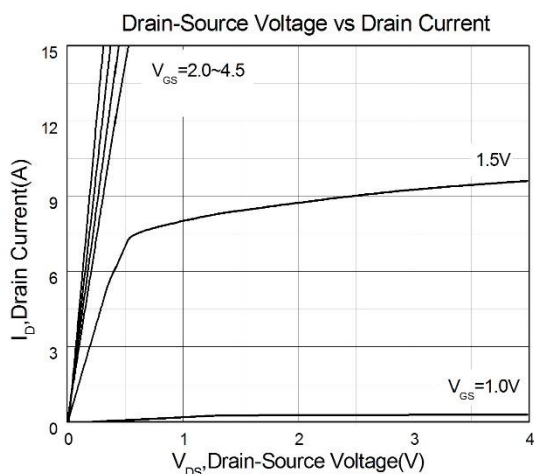


Figure 1

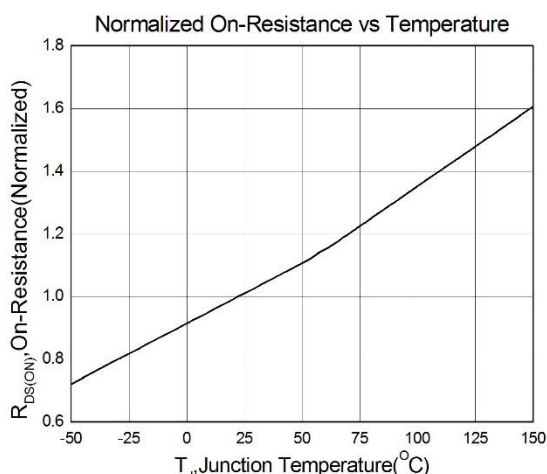


Figure 2

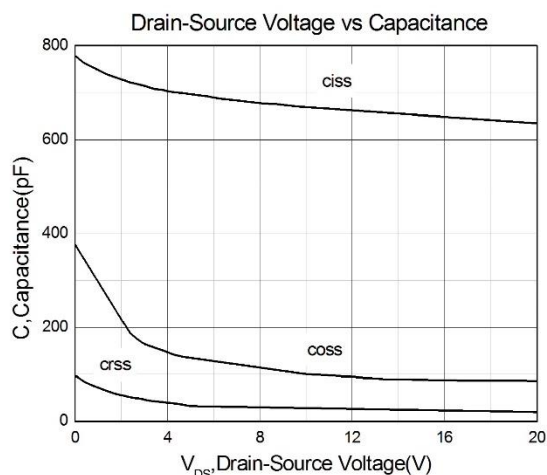


Figure 3

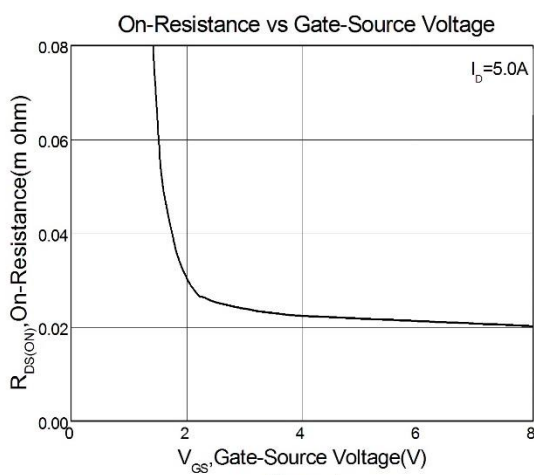


Figure 4

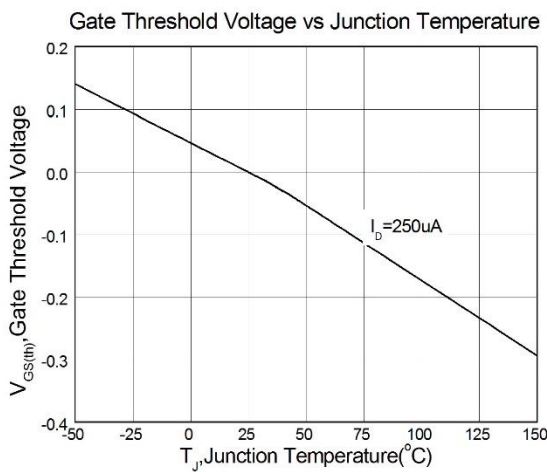


Figure 5

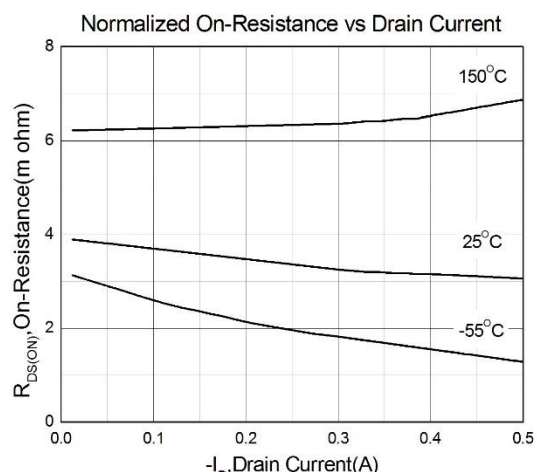


Figure 6



# N-Channel Enhancement MOSFET

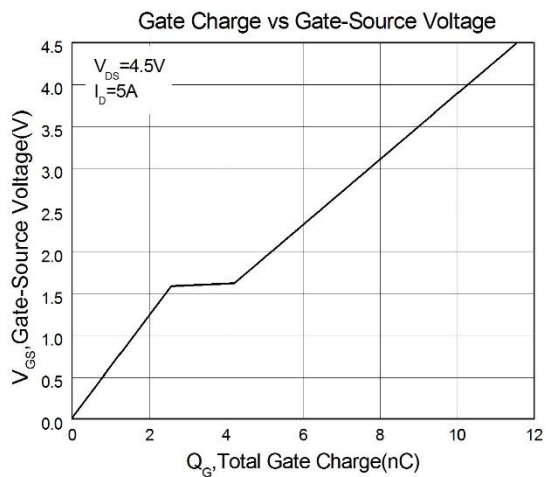


Figure 7

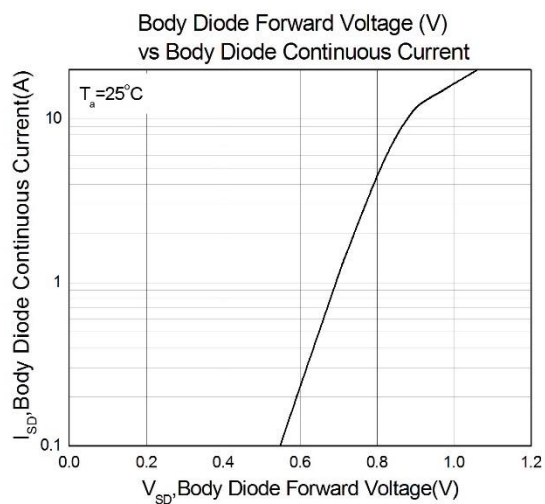


Figure 8



Test Circuits & Waveforms

Figure 9: Gate Charge Test Circuit

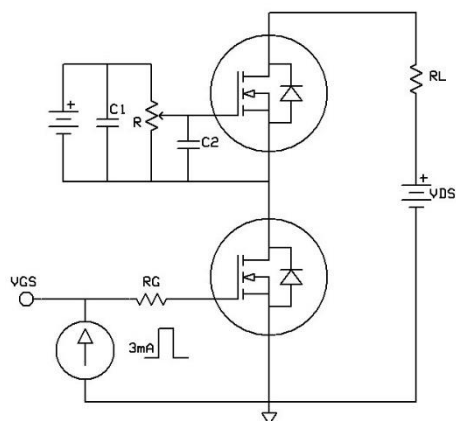


Figure 10: Gate Charge Waveform

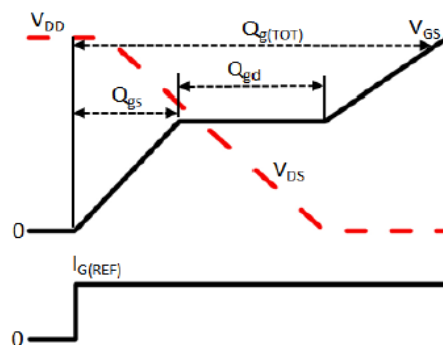


Figure 11: Switching Time Test Circuit

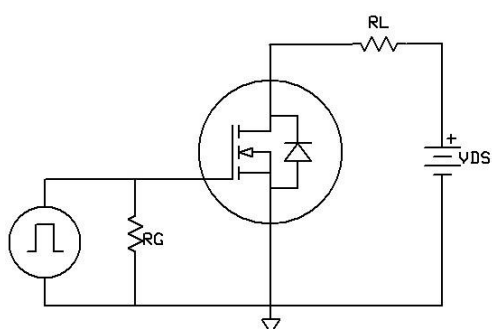


Figure 12: Switching Time Waveform

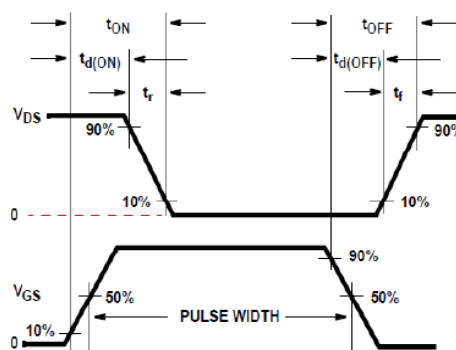


Figure 13: Unclamped Energy Test Circuit

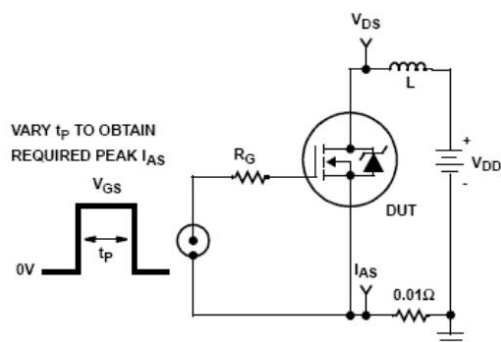
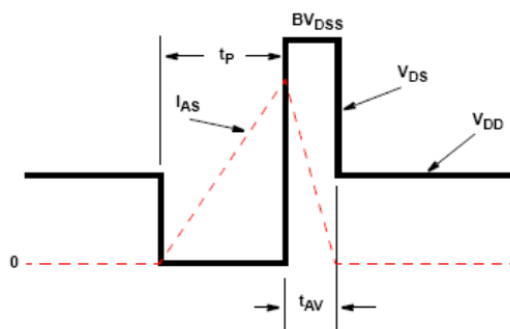
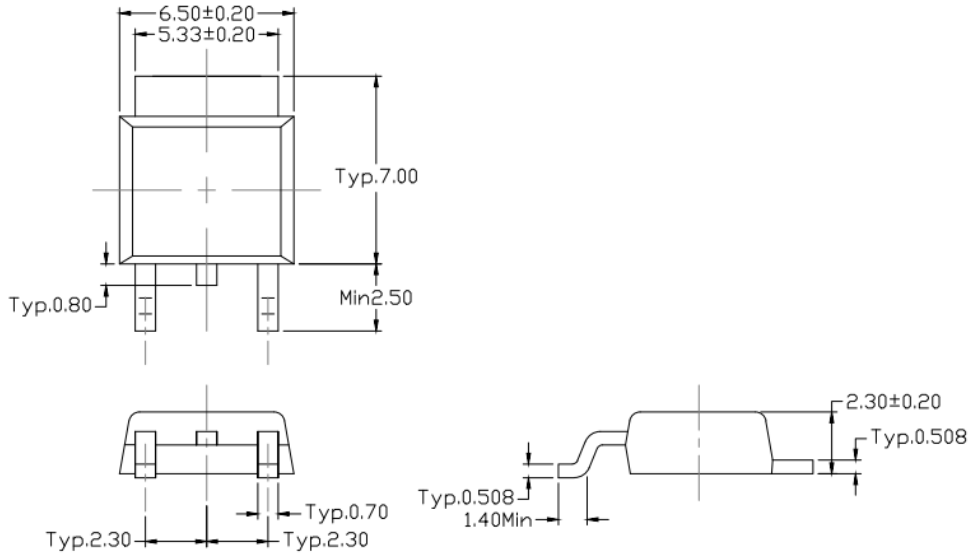


Figure 14: Unclamped Energy Waveforms



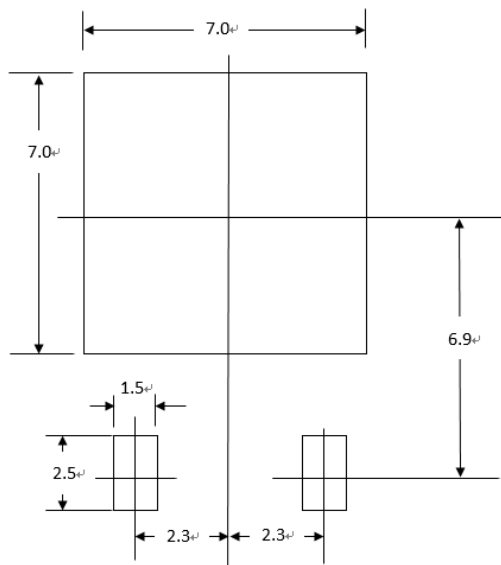


Package Dimension (TO-252)



Dimensions in mm unless otherwise stated

Recommended pad layout for surface mount leadform



Dimensions in mm unless otherwise stated



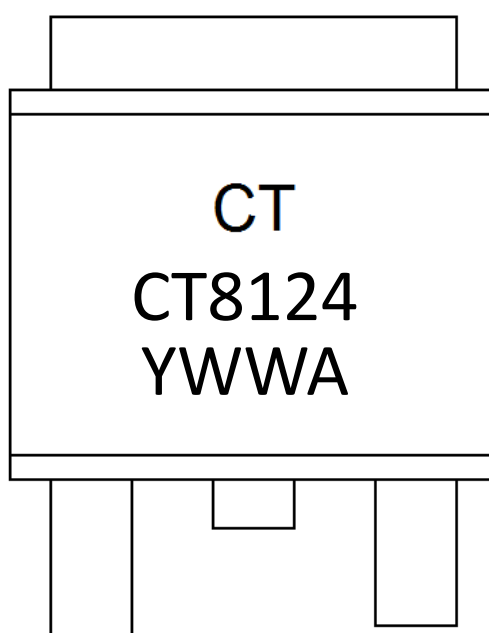


**CT8124-T52**

**N-Channel Enhancement MOSFET**

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## Marking Information



CT : Denotes “ CT Micro”  
8124 : Device Number  
Y : Fiscal Year  
WW : Work Week  
A : Production Code

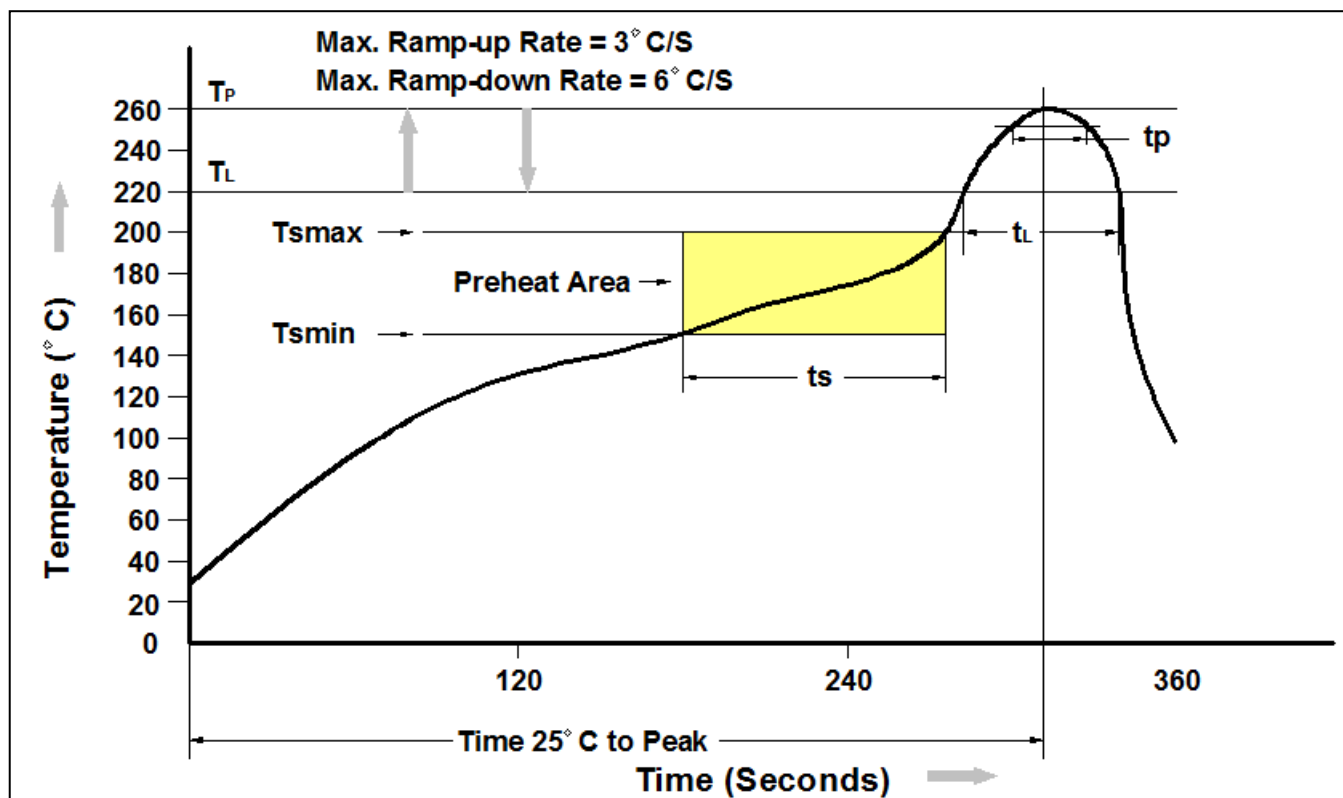
## Ordering Information

<b>Part Number</b>	<b>Description</b>	<b>Quantity</b>
CT8124-T52	TO-252 Reel	2500 pcs



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Reflow Profile



Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T <sub>smin</sub> )	150°C
Temperature Max. (T <sub>smax</sub> )	200°C
Time (t <sub>s</sub> ) from (T <sub>smin</sub> to T <sub>smax</sub> )	60-120 seconds
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.
Liquidous Temperature (T <sub>L</sub> )	217°C
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60 – 150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max
Time 25°C to Peak Temperature	8 minutes max.



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